

AccoTEST 培训热点 Q&A 集合

----2023(第一期)

▶ 软件相关:

1. <u>使用VS2013 开发时, 找不到APA 功能入口?</u>

- (1) 安装 VS2013 及 AccoTEST 软件时,要求先安装 VS2013,再安装 AccoTEST 软件,否则可能导致 APA 工具无法正确安装;安装 AccoTEST 软件时,先关闭 VS2013;
- (2) 若软件已经安装完成,也可点击开始菜单,找到 AccoTestSTS8200CROSS
 (STS8200)或者 AccoTEST System (STS8300)文件,点击子文件夹下 Install VS2013 Tools 文件;



在弹出 Install VS2013 Tools 窗口界面会自动进行安装 vs2013 插件,待跳出"安装 VS2013 完成"时,如下图,可以按任意键退出该窗口。之后可以确认一下 APA 是 否已安装好;

C:\WINDOWS\System32\cmd.exe			×
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(3) 另一种方式,可以找到 AccoTEST 软件安装目录下的 VS2013ToolsSetup.bat,以管 理员身份运行,重新安装 APA 工具;

VS2013ToolsSetup.bat

(4) 经以上步骤仍无法找到 APA,可通过工具栏 TOOLS 下的 Extensions and Updates,

点击 APA 右侧的 Enable 按钮使能 APA 工具, 然后重启 VS2013。

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2. <u>点击测试时,软件提示 "硬件检查失效/Hardware</u>

Configuration check Failed"?



 检查 TestUI -> Options 下是否开启 Enable Hardware Configuration Check, 若开启则会对当前测试机内的配置和程序中 HardwareCfg()函数中的配置进行检 查,若当前测试机内的配置少于 HardwareCfg()中的配置,则会报错。若只是调 试阶段,可将该选项屏蔽。



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注意:

若 HardwareCfg()中未做任何配置, Online 状态下, 软件也可能会报错。

若 Options 界面 Enable hardware configuration check 选项灰色不可更改:

(1) 请确认程序中是否有强制开启硬件配置检查功能

STSSetHardwareCheck();

(2) 8300软件版本 200814pr4.0及以后的版本,PGS版本 1004及以上,会强制开启该功能,用户只能通过程序接口设置该功能启用或禁用(默认强制开启)。

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2. STS8300 调用测试程序进行诊断时若出现以上提示,首先确认在 Control 界面,

System Option 中确认是否勾选如下选项,若已勾选建议先去掉。

ystem Setting	
Open Project With	
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3. <u>STS8300 PinPlanner 界面,各工位绑定的通道标红,无法保</u>

<u>存?</u>

PinPlanner 指向的 slot 文件内容与当前 PinPlanner 界面使用的资源不匹配时,不匹配的通道会以红色标注。出现以上现象,建议重新打开 PinPlanner 工具栏中的 Setting->Config File,如下图。

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	4Pin 🗸	Auto Modify (Comment	∇	NoSite	Site[1]	Sitel21		
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2	fovie1	Config File				Slot19_1	Slot19_5		
3	fovie2	fovie2	FOVIe			Slot19_2	Slot19_6		
4	fovie3	fovie3	FOVIe			Slot19_3	Slot19_7		
	i.								



Config File		_ ×
C:\AccoTEST\	AccoTEST System_backup\Config.slot	
	Modfly Slot	
	ОК	Cancel

查看 Slot 文件路径是否正确,可重新选择正确路径,也可以通过 Modify Slot 重新编辑/修改 Slot 文件,保持与当前 PinPlanner 设置一致即可。

▶ 硬件相关:

4. <u>STS8300 DCM 进行多工位调试时,有些工位的比较结果在</u> FailMap 中无法完整地获取 (200814_r p3.1 及以下版本) ?

DCM 单板 64 个通道,每 16 个通道为一个 Bank,每个 Bank 共享 1023 行失效存储空间,每组通道中任意一个通道失效,则占用一个失效存储行,1023 行失效存储空间占满后,失效行不再进行存储。

同一控制器的失效存储只保存前 1023 行失效行,这样当通道的失效行总数超过 1023 行,或者失效行在其它通道的 1023 个失效行之后,那么该通道的部分失效 信息将无法保存。以上失效存器空间只影响 SaveFailMap()失效图信息以及 GetCaptureData()获取数据。

因此,当多个工位的比较通道在同一个控制器上时,不建议使用 GetCaptureData(),例如工位1的比较通道为CH1,工位2的比较通道为CH3,此 时工位1和工位2的比较通道在同一控制器内,共享1023个失效存储行,如果工 位1或者工位2没有芯片或者芯片Fail,那么会影响另一个工位的失效行存储。

Sit	e Cou	int:2 🗘						
		-		CH-S	Site 1	CH-	Site2	
	Pin	CH-Count	Comment	Slot	Ch	Slot	Ch	
1	PIN1	1		9	1	9	3	
2	PINO	1		9	0	9	2	



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如上图,工位1的失效图只显示两行失效,但失效行数提示1023行。

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工位2由于未放芯片,导致大量失效行占满了失效存储空间,导致工位1在 失效存储空间占满后,部分失效信息无法存储。

针对以上问题,提供如下解决方案:先进行单工位调试,向量文件中只保留工位1的通道,其他工位临时删除或绑定至其他 Bank。

为避免以上问题在程序开发阶段造成困扰,强烈建议调试时,开启 Enable Log 功能(TestUI 界面->Option),如下图所示,当失效存储空间占满后,软件将 在 System Message Handler 中弹出提示信息,如下图。



Options					
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AccoTEST Syst	tem Message Hand	iler			
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5. <u>使用 STS8300 测试时,CBITe 上的 DUT POWER(+5V,+12V,</u> <u>±15V 电源)不受控,THB 上的指示灯熄灭,重新 Load 程序可</u> 以恢复?

排查程序中是否使用了 CBITe 的 Init()函数,该函数会将 DUT POWER 的状态关闭, 所有 CBITe 控制位置为初始状态(板卡内部为 OD 输出);而重新 Load 程序时,会默认 将 CBITe 的 DUT POWER 开启。若程序中必须关闭 DUT POWER,用户可通过 SetDutPower 来控制 DUT POWER 的开和关。

6. <u>使用向量文件时,加载成功后,程序中要让不同工位运行不同的</u> <u>向量,如何实现?</u>

dcm.SetWaveDataParam("G_ALLPIN", "A1", 10, 20);
BYTE pbySiteWaveData[SITE_NUM][3] = {{0x5A,0xA5,0x05},{0xAA,0x55,0x0A},{0xA5,0xA5,0x0A},{0x5A,0xA5,0x05}};
for (int nSiteIndex = 0; nSiteIndex< SITE_NUM; ++nSiteIndex)
{
 dcm.SetSiteWaveData(nSiteIndex, pbySiteWaveData[nSiteIndex]);
}
dcm.WriteWaveData();</pre>

STS8200 中,定义为 DIO_PLUS 的类,可通过 ModifyLinePattern(), 单行修改硬件中已加载的向量行。或通过 ModifyMultiLinePatterns(),一次修改多行向量行。

STS8300中,可通过SetWaveDataParam(),SetSiteWaveData()以及WriteWaveData()

修改已加载的向量行。



详情可参考 STS8200、STS8300 最新编程手册。